

7th National Conference
on
Advances in Metrology

AdMet-2021

(March 5th-6th, 2021)

Theme

**Sensors & Advance Materials for
Measurement & Quality Improvement**

at

**Maharaja Surajmal Institute
of Technology (MSIT)**
C-4, Janakpuri, New Delhi

www.msit.in



Jointly organized by:

CSIR-National Physical Laboratory (CSIR-NPL),
Metrology Society of India (MSI) and
National Accreditation Board for Testing
Calibration Laboratories (NABL)



SCOPE

The following topics will be covered in AdMet-2021:

- Frontiers in metrology and future trends.
- Advances in physical, chemical, Bio, electrical, optical and smart sensors, etc. for industrial application & automation.
- Advanced materials for sensing, instrumentation and measurement:
 - a) Magnetic & optoelectronic materials, superconductors, thin films, piezoelectric and semiconductor devices and more.
 - b) Nanotechnology/Nanometrology and MEMS
- Recent advances in sensor technology and advanced materials for metrology application in environment, climate change, health care and biomedical monitoring.
- Measurement techniques for physico-mechanical, electrical, electronic and chemical parameters.
- Primary standards, calibration, testing and traceability related issues for industrial applications.
- Role of metrology in quality control, quality improvement and quality assurance.
- Issues related to quality management, accreditations and legal metrology.

IMPORTANT DATES

Last date of receipt of Full Article	5 th Feb. 2021
Acceptance Notifications	15 th Feb. 2021
Last date of Registration	20 th Feb. 2021
Last date of Camera Ready paper submission	25 th Feb. 2021

You are requested to submit scholarly full-length research paper, based on original and unpublished work. If only abstract received, it will be published in AdMet conference proceedings only.

Manuscript Submission link:

<https://easychair.org/conferences/?conf=admet2021>

Please mail Abstract or any query at: admet.2021@gmail.com

Kindly Visit <https://admet2021.com/> for latest updates.

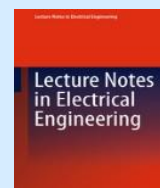
CONTACT DETAILS

Dr. Ajay Gahlot (Convener)	Mob. 9871047332
Dr. Yogendra Arya (Co-convener)	Mob. 9891484801
Dr. Aman Dahiya (Co-convener)	Mob. 9971094326

RESEARCH AWARDS

Best paper/poster will be awarded with cash prize and certificates.

PUBLICATIONS



All accepted and presented papers will be published as Book Chapters in **Scopus Indexed Edited Book by Springer: *Lecture Notes in Electrical Engineering***



Selected high quality research papers will be published in the special issue "Sensors and Advanced Materials for Futuristic Metrological Applications" of **MAPAN** (SCIE indexed journal published by Springer with **Impact Factor of 1.033**).

ORGANIZERS

Patrons

Sh. Kaptan Singh, President, SMES
Prof. M.P. Poonia, Vice-Chairman, AICTE

Organizing Chair

Prof. K.P. Chaudhary, Director, MSIT

KEYNOTESPEAKERS

1. **Dr. Toshiyuki Takatsuji**, Director, Research Institute for Engineering Measurement, Japan
2. **Prof. K.K. Aggarwal**, Chairperson-NBA, Former Vice Chancellor GGSIPU, New Delhi
3. **Dr. D.K. Aswal**, Director, CSIR-NPL, New Delhi
4. **Dr. Krishan Lal**, Former INSA Chairman, Ex-Director, NPL
5. **Dr. R.K. Kotnala**, Chairman-NABL, Raja Raman Fellow, DAE
6. **Dr. A. Sengupta**, Honorary Distinguished Research Professor
7. **Dr. AvanishSrivastava**, Director, CSIRAdvanced Materials and Processes Research Institute, Bhopal
8. **Mr. N. Venkateswaran**, CEO, NABL
9. **Prof. K.P. Chaudhary**, Director, MSIT, Former Chief-scientist CSIR-NPL
10. **Dr. Sanjay Yadav**, VP MSI, HOD, Physico-Mechanical Metrology Division, Editor-in-chief, MAPAN, CSIR-NPL
11. **Dr. Ranjana Mehrotra**, Former Chief Scientist NPL, VP MSI
12. **Prof. Ravinder Agarwal**, Head of Electrical & Instrumentation Engg. Deptt., Thapar Institute of Engineering & Technology

REGISTRATION FEES

Registration may be done by filling up the registration form and sending the same to the conference organizer.

Category	INR
Academician	2,500/-
MSI members	2,000/-
Research Scholars/Students/Attendees	1,000/-
Corporate/Industry/ Delegates	3,000/-

Foreign Academician/ Research Scholars USD 100

Participants are requested to make payment for registration via link provided on website or through DD in favour of Maharaja Surajmal Institute of Technology, payable at New Delhi.

For sponsorship opportunity, please visit: <https://admet2021.com/sponsor.php>

MAHARAJA SURAJMAL INSTITUTE OF TECHNOLOGY (MSIT)

MSIT is established in 2001 under the aegis of Surajmal Memorial Education Society (SMES) to emulate & cherish the great qualities of Maharaja Surajmal. Since its inception the institute has developed impressive Hi-tech infrastructure, expertise and modernized resources for imparting high-quality engineering education. The institute runs in two shifts First/Morning shift and Second/Evening shift providing Bachelor of Technology (B.Tech.) in CSE, IT, ECE and EEE streams. MSIT is NAAC Grade A accredited, ISO-9001:2015 certified Institute and all programmes are NBA accredited. MSIT has been ranked 3rd in North Zone and 18th across India among top private engineering colleges by India Today Magazine-2020, best private engineering college in Delhi. MSIT prominently appears in the IP University tally of Gold Medals in academics and sports, excellent placement record in reputed companies, highly experienced, qualified and enthusiastic research-oriented faculty.

MSIT is hub for on campus placement for global companies like Google, Microsoft, Amazon, SAP Labs, Accenture, Samsung, Yamaha and many more. MSIT is recipient of NEA (National Employability Award) for

the last five successive years, being one amongst the top 10% Engineering College at the national level having huge employability potential.

METROLOGY SOCIETY OF INDIA (MSI)

The Metrology Society of India (MSI) was founded in Jan. 1984 to promote and disseminate Metrology in its varied aspects. The main objective of MSI is to provide a forum for exchange of ideas, opinions and experiences of persons and agencies connected with metrology and assist the Government in formulating legislative and other measures for future growth in metrology in the country. MSI is publishing since October 1985, MAPAN-Journal of Metrology Society of India, exclusively devoted to metrology.

CSIR-NPL

CSIR-NPL established in 1947, a signatory to the MRA of CIPM, has been assigned the responsibility to carry out the work related to realization, establishment, custody maintenance, reproduction and improve continuously by research, the standards of physical and chemical measurements with highest level of accuracies and traceability to the international measurement system. CSIR-NPL objective is to assist the industries and other agencies of the country in their requirements of precision measurement and calibration of instruments, as well as in the development of related devices, processes and techniques.

Traceability of standards to SI units is achieved either by calibrations performed at the NPL or the NMI of another country that has achieved less uncertainty in the value of a standard. Equivalence of these national standards with international standards is achieved by participating in international inter comparisons of standards.

NABL

NABL has been established with the objective of providing Government, Industry Associations and Industry in general with a scheme of Conformity Assessment Body's accreditation which involves third-party assessment of the technical competence of testing

including medical and calibration laboratories, proficiency testing providers and reference material producers. Accreditation process details are provided in NABL 100 "General information Brochure". NABL is Mutual Recognition Arrangements (MRA) signatory to ILAC as well as APAC for the accreditation of Testing and Calibration Laboratories (ISO/IEC 17025), Medical Testing Laboratories (ISO 15189), Proficiency Testing Providers (PTP) (ISO/IEC 17043) and Reference materials producers (RMP). Such MRA reduces technical barrier to trade and facilitates acceptance of test/ calibration results between countries which MRA partners represent.

The disciplines and groups for which the accreditation services are offered in the respective fields are listed in: NABL 120, NABL 112, NABL 180 and NABL 190.

NABL publishes documents for the CABs, Assessors and its own use. All NABL documents meant for the use by persons outside NABL can be accessed free of cost at NABL website.

ABOUT CONFERENCE

The 7th National Conference AdMet-2021 on Sensors & Advance Materials for Measurement & Quality Improvement is an effort to highlight and discuss the technological developments in the areas of sensor modeling, measurement, advanced material for industrial applications, automation and quality control.

The goal of AdMet-2021 is to provide an opportunity for metrologists, scientists, engineers, academicians and students from research institutes and industrial establishments for interdisciplinary discussions and interactions to exchange and share their ideas, work experiences, trends and concerns to explore the future directions to identify thrust areas of R&D. The conference perspective is to explore collaborations with fellow scientists/engineers in the areas of sensors, advance materials, measurement and quality improvement. Technical papers describing original, unpublished research work, experimental efforts, industrial and commercial developments in all aspects of sensors and advanced materials are solicited.